

ANALOG 1.8 nV/√Hz, 36 V Precision Single and Dual DEVICES **Amplifier**

PreliminaryTechnical Data

ADA4004-1 and ADA4004-2

FEATURES

Very low voltage noise: 1.8 nV/√Hz Low input bias current: 100 nA maximum Offset voltage: 100 µV maximum

High gain: 120 dB

Wide bandwidth: 12 MHz ±5 V to ±15 V operation

APPLICATIONS

Precision instrumentation Filter blocks Microphone preamplifier **Industrial control** Thermocouples and RTDs **Reference buffers**

GENERAL DESCRIPTION

The ADA4004-1 and ADA4004-2 are single and dual precision bipolar op amps that featuring a 1.8 nV/ $\sqrt{\text{Hz}}$ precision, 40 μ V offset, 0.7 μV/°C drift, 12 MHz bandwidth, and low 1.7 mA/amplifier supply current.

The ADA4004 is designed on the high performance *i*Polar[™] process, enabling improvements such as reduced noise and power consumption, increased speed and stability, and a smaller footprint size. Novel design techniques enable the ADA4004 to achieve 1.8 nV/√Hz voltage noise density and a low 6 Hz 1/f noise corner frequency while consuming just 1.7 mA/amplifier. The small package saves board space, reduces cost, and improves layout flexibility.

Applications for these amplifiers include high precision controls, PLL filters, high performance precision filters, medical and analytical instrumentation, precision power supply controls, ATE, and data acquisition systems.

The high performance ADA4004 is offered in the very small 5lead SOT and 8-lead SOIC for the single (ADA4004-1) and the 8-lead MSOP for the dual (ADA4004-2), lead-free, surfacemount packages. Operation is fully specified from ±5 V to ±15 V from -40° C to $+125^{\circ}$ C.

PIN CONFIGURATIONS

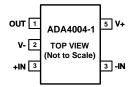


Figure 1..5-Lead SOT (RJ-5)

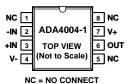


Figure 2. 8-Lead SOIC (R-8)



8-Lead MSOP (RM-8)

ADA4004-1 and ADA4004-2

SPECIFICATIONS

 $V_S = \pm 5.0$ V, $V_{CM} = 0$ V, $T_A = +25$ °C, unless otherwise specified.

Table 1.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS				·		
Offset Voltage	Vos			40	140	μV
		$-40^{\circ}C \le T_{A} \le +125^{\circ}C$			300	μV
Input Bias Current	I _B			40	85	nA
	_	-40°C ≤ T _A ≤ +125°C			165	nA
Input Offset Current	los			40	85	nA
		$-40^{\circ}\text{C} \le \text{T}_{\text{A}} \le +125^{\circ}\text{C}$			100	nA
Input Voltage Range		13 S = 1 1 2 S	-3.5		+3.5	V
Common-Mode Rejection Ratio	CMRR	$V_{CM} = -3.0 \text{ V to } +3.0 \text{ V}$	105	111		dB
		$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$	95	110		dB
Open-Loop Gain	Avo	$R_L = 2 k\Omega$, $V_O = -2.5 V to +2.5 V$	250	400		V/mV
	7.00	$-40^{\circ}\text{C} \le \text{T}_{A} \le +125^{\circ}\text{C}$	170	100		V/mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$	$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$.,,	0.7	1	μV/°C
OUTPUT CHARACTERISTICS	ΔV05/Δ1	-40 C S 1A S + 125 C		0.7	•	μν, σ
Output Voltage High	V _{OH}	$R_L = 2 k\Omega$ to ground	3.7	3.9		V
	VOH	$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$	3.4	3.6		V
Output Voltage Low	Vol	$R_L = 2 k\Omega$ to ground	3.4	–3.6	-3.55	V
Output voltage Low	VOL	$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$		-3.6	-3.55 -3.5	V
Short Circuit Limit	1	-40 C ≤ I _A ≤ +125 C			-3.5	1 -
	I _{SC}	100C (T. () 10F0C		25		mA mA
0		$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$. 10		
Output Current POWER SUPPLY	lo	$V_{OUT} = \pm 3.6 \text{ V}$		±10		mA
	DCDD		110	110		-ID
Power Supply Rejection Ratio	PSRR	$V_S = \pm 5.0 \text{ V to } \pm 15.0 \text{ V}$	110	118		dB
		$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$	110			dB
Supply Current/Amplifier	Isy				1.7	mA
		-40°C ≤ T _A ≤ +125°C			2.0	mA
DYNAMIC PERFORMANCE						
Slew Rate	SR	$R_L = 2 k\Omega$ to ground		2.7		V/µs
Gain Bandwidth Product	GBP			12		MHz
NOISE PERFORMANCE						
Voltage Noise	e _{n p-p}	0.1 Hz to 10 Hz		0.1		μV p-p
Voltage Noise Density	en	f = 1 kHz		1.8		nV/√H
Current Noise Density	İn	f = 10 Hz		3.5		pA/√H
Current Noise Density	İn	f = 200 Hz		1.2		pA/√H

 $V_{_{S}}$ = ±15 V, $V_{_{CM}}$ = 0 V, T_{A} = +25°C, unless otherwise specified.

Table 2.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS						
Offset Voltage	Vos			40	125	μV
		$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$			270	μV
Input Bias Current	I _B			40	90	nA
		$-40^{\circ}\text{C} \le \text{T}_{A} \le +125^{\circ}\text{C}$			165	nA
Input Offset Current	los				60	nA
		$-40^{\circ}\text{C} \le \text{T}_{A} \le +125^{\circ}\text{C}$			100	nA
Input Voltage Range			-12.5		+12.5	٧
Common-Mode Rejection Ratio	CMRR	$V_{CM} = -12.5 \text{ V to } +12.5 \text{ V}$	110	113		dB
		$-40^{\circ}\text{C} \le \text{T}_{A} \le +125^{\circ}\text{C}$	100	104		dB
Open-Loop Gain	Avo	$R_L = 2 k\Omega$, $V_O = -12.5 V$ to $+12.5 V$	500	1200		V/mV
		-40°C ≤ T _A ≤ +125°C	250	500		V/mV
Offset Voltage Drift	ΔV _{os} /ΔT	-40°C ≤ T _A ≤ +125°C		0.7	1	μV
OUTPUT CHARACTERISTICS						
Output Voltage High	V _{OH}	$R_L = 2 k\Omega$ to ground	13.4	13.6		V
		-40°C ≤ T _A ≤ +125°C	13.1	13.3		V
Output Voltage Low	V _{OL}	$R_L = 2 k\Omega$ to ground		-13.3	-13.2	V
		-40°C ≤ T _A ≤ +125°C		-13.25	-13.18	٧
Short Circuit Limit	I _{SC}			25		mA
Output Current	lo	$V_{OUT} = \pm 13.6 \text{ V}$		±10		mA
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	$V_S = \pm 5.0 \text{ V to } \pm 15.0 \text{ V}$	110	118		dB
		-40°C ≤ T _A ≤ +125°C	110			dB
Supply Current/Amplifier	I _{SY}				1.775	mA
		$-40^{\circ}\text{C} \le T_{A} \le +125^{\circ}\text{C}$			2.10	mA
DYNAMIC PERFORMANCE						
Slew Rate	SR	$R_L = 2 k\Omega$ to ground		2.7		V/µs
Gain Bandwidth Product	GBP			12		MHz
NOISE PERFORMANCE						
Voltage Noise	e _{n p-p}	0.1 Hz to 10 Hz		0.15		μV p-p
Voltage Noise Density	e _n	f = 1 kHz		1.8		nV/√Hz
Current Noise Density	in	f = 10 Hz		3.5		pA/√Hz
Current Noise Density	İn	f = 200 Hz		1.2		pA/√Hz

ABSOLUTE MAXIMUM RATINGS

Table 3.

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Parameter	Rating			
Supply Voltage	±18 V/+36 V			
Input Voltage	±V supply			
Differential Input Voltage	±V supply			
Output Short-Circuit Duration to GND	Indefinite			
Storage Temperature Range	−65°C to +150°C			
Operating Temperature Range	-40°C to +125°C			
Junction Temperature Range	−65°C to +150°C			
Lead Temperature (Soldering 60 sec)	300°C			

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.